

<b>Notice of References Cited</b>	Application/Control No. 10/799,335	Applicant(s)/Patent Under Reexamination TOMASINI ET AL.	
	Examiner G. Nagesh Rao	Art Unit 1722	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,026,219	04-2006	Pomarede et al.	438/285
*	B	US-2002/0173130	11-2002	Pomarede et al.	438/592
*	C	US-2002/0125471	09-2002	Fitzgerald et al.	257/19
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mayer, J. and Lau, S.S., Electronic Materials Science: For Integrated Circuits in Si and GaAs, 1990, Macmillan, P. 40.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.